



# STD5N95K3, STF5N95K3 STP5N95K3, STU5N95K3

N-channel 950 V, 3 Ω, 4 A, DPAK, TO-220, TO-220FP, IPAK  
Zener-protected SuperMESH3™ Power MOSFET

## Features

Type	V <sub>DSS</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>	P <sub>w</sub>
STD5N95K3	950 V	< 3.5 Ω	4 A	90 W
STF5N95K3	950 V	< 3.5 Ω	4 A	25 W
STP5N95K3	950 V	< 3.5 Ω	4 A	90 W
STU5N95K3	950 V	< 3.5 Ω	4 A	90 W

- 100% avalanche tested
- Extremely large avalanche performance
- Gate charge minimized
- Very low intrinsic capacitances
- Zener-protected

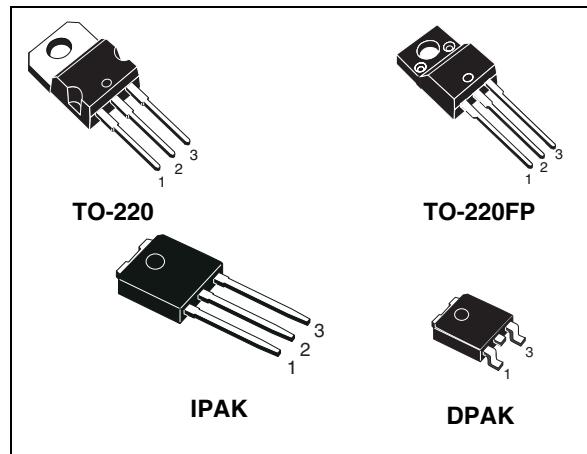
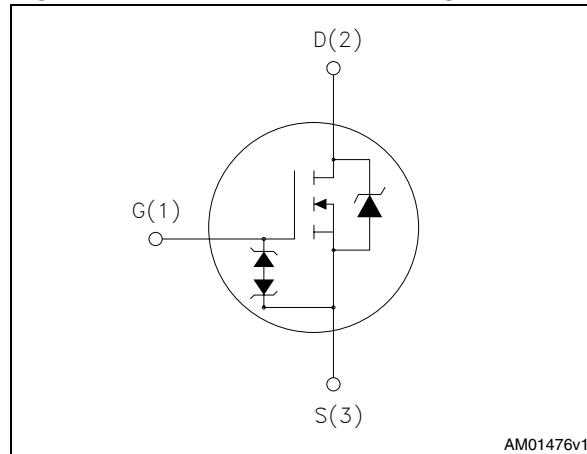


Figure 1. Internal schematic diagram



AM01476v1

Table 1. Device summary

Order codes	Marking	Packages	Packaging
STD5N95K3	5N95K3	DPAK	Tape and reel
STF5N95K3	5N95K3	TO-220FP	Tube
STP5N95K3	5N95K3	TO-220	Tube
STU5N95K3	5N95K3	IPAK	Tube

## Contents

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# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value				Unit
		TO-220	TO-220FP	IPAK	DPAK	
$V_{GS}$	Gate- source voltage	30		V		
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	4	$4^{(1)}$	4		A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	3	$3^{(1)}$	3		A
$I_{DM}^{(2)}$	Drain current (pulsed)	16	$16^{(1)}$	16		A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	90	25	90		W
$I_{AR}$	Avalanche current, repetitive or non-repetitive (pulse width limited by $T_J$ max)	4		A		
$E_{AS}$	Single pulse avalanche energy (starting $T_J = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ )	100		mJ		
$dv/dt^{(3)}$	Peak diode recovery voltage slope	5		V/ns		
$V_{ISO}$	Insulation withstand voltage (AC)		2500			
$T_J$ $T_{stg}$	Operating junction temperature Storage temperature	-55 to 150		°C		

1. Limited only by maximum temperature allowed
2. Pulse width limited by safe operating area
3.  $I_{SD} \leq 4\text{ A}$ ,  $di/dt \leq 100\text{ A}/\mu\text{s}$ , peak  $V_{DS} \leq V_{(BR)DSS}$

**Table 3. Thermal data**

Symbol	Parameter	Value				Unit
		TO-220	TO-220FP	IPAK	DPAK	
$R_{thj-case}$	Thermal resistance junction-case max	1.39	5	1.39		°C/W
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.50	100			°C/W
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb max			50		°C/W
$T_J$	Maximum lead temperature for soldering purpose	300				°C/W

1. When mounted on 1inch<sup>2</sup> FR-4 board, 2 oz Cu

## 2 Electrical characteristics

(T<sub>case</sub> =25 °C unless otherwise specified)

**Table 4. On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0	950			V
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = Max rating V <sub>DS</sub> = Max rating, T <sub>C</sub> =125 °C			1 50	μA μA
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20 V; V <sub>DS</sub> =0			10	μA
V <sub>GS(th)</sub>	Gate threshold voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 100 μA	3	4	5	V
R <sub>DS(on)</sub>	Static drain-source on resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2 A		3	3.5	Ω

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	V <sub>DS</sub> = 25 V, f = 1 MHz, V <sub>GS</sub> = 0	-	460 38 1	-	pF pF pF
C <sub>o(tr)<sup>(1)</sup></sub>	Equivalent capacitance time related	V <sub>DS</sub> = 0 to 760 V, V <sub>GS</sub> = 0	-	970	-	pF
C <sub>o(er)<sup>(2)</sup></sub>	Equivalent capacitance energy related	V <sub>DS</sub> = 0 to 760 V, V <sub>GS</sub> = 0	-	15	-	pF
R <sub>g</sub>	Gate input resistance	f=1 MHz open drain	-	5.5	-	Ω
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	V <sub>DD</sub> = 760 V, I <sub>D</sub> = 4 A, V <sub>GS</sub> = 10 V <i>(see Figure 20)</i>	-	19 4.7 12	-	nC nC nC

1. Time related is defined as a constant equivalent capacitance giving the same charging time as C<sub>oss</sub> when V<sub>DS</sub> increases from 0 to 80% V<sub>DSS</sub>
2. Energy related is defined as a constant equivalent capacitance giving the same stored energy as C<sub>oss</sub> when V<sub>DS</sub> increases from 0 to 80% V<sub>DSS</sub>

**Table 6. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 475 \text{ V}$ , $I_D = 2 \text{ A}$ , $R_G = 4.7 \Omega$ , $V_{GS} = 10 \text{ V}$ (see Figure 19)	-	17	ns	
$t_r$	Rise time			7		
$t_{d(off)}$	Turn-off-delay time			32	ns	
$t_f$	Fall time			18		

**Table 7. Source drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$I_{SD}$	Source-drain current		-	4	16	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)					
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 4 \text{ A}$ , $V_{GS} = 0$	-	1.6	V	
$t_{rr}$	Reverse recovery time	$I_{SD} = 4 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ (see Figure 21)	-	410	ns	$\mu\text{C}$
$Q_{rr}$	Reverse recovery charge			3.5		
$I_{RRM}$	Reverse recovery current			17		
$t_{rr}$	Reverse recovery time	$I_{SD} = 4 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ $T_J = 150^\circ\text{C}$ (see Figure 21)	-	516	ns	$\mu\text{C}$
$Q_{rr}$	Reverse recovery charge			4.1		
$I_{RRM}$	Reverse recovery current			16		

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

**Table 8. Gate-source Zener diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$BV_{GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1 \text{ mA}$ (open drain)	30	-		V

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220

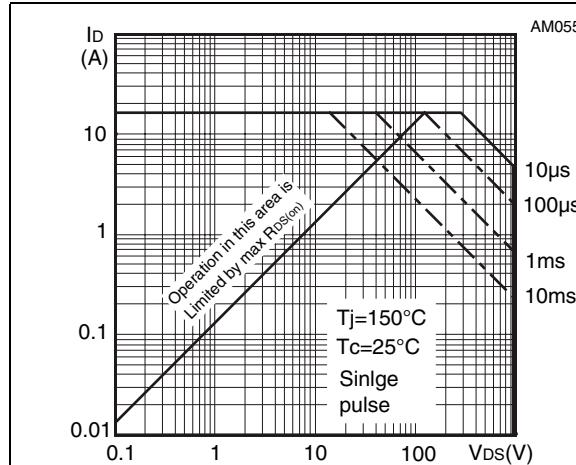


Figure 3. Thermal impedance for TO-220

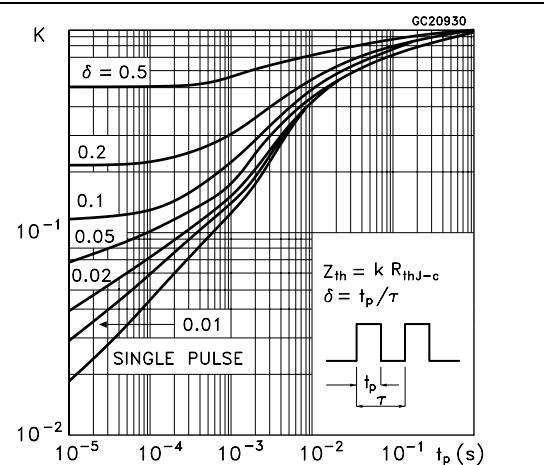


Figure 4. Safe operating area for TO-220FP

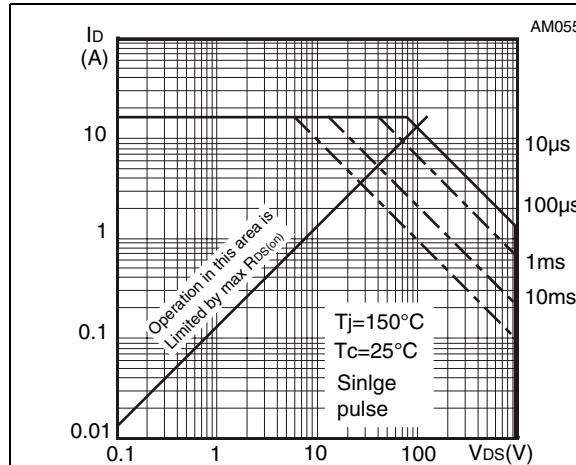


Figure 5. Thermal impedance for TO-220FP

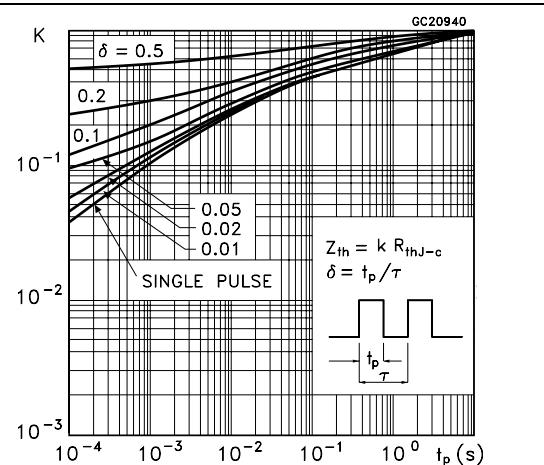


Figure 6. Safe operating area for IPAK, DPAK

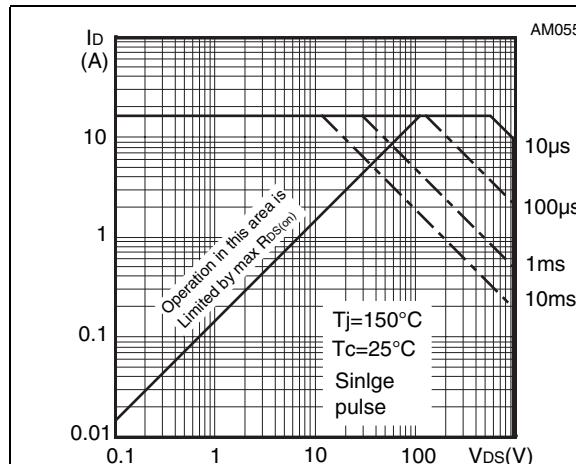
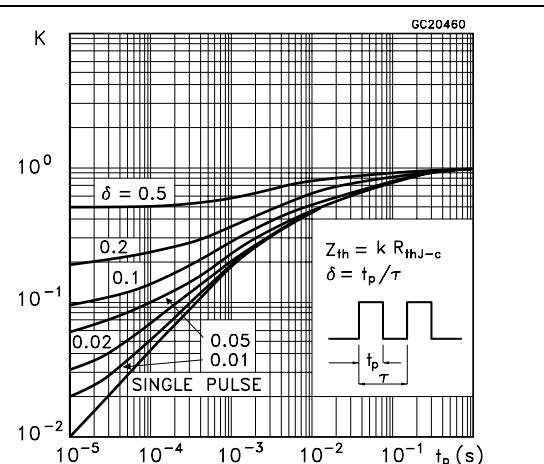
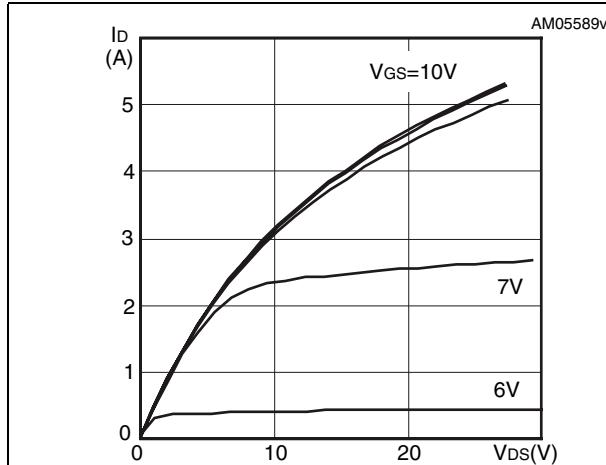
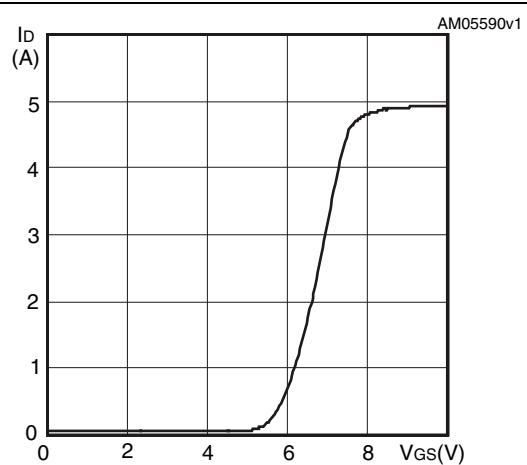
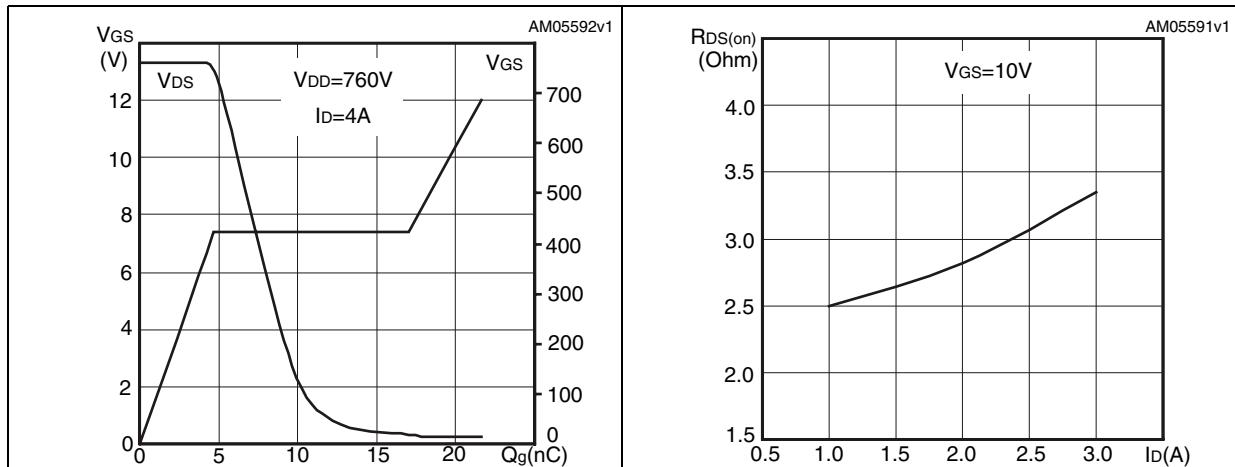
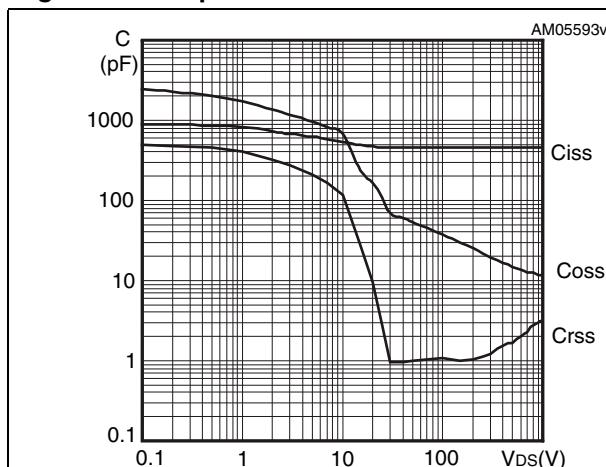
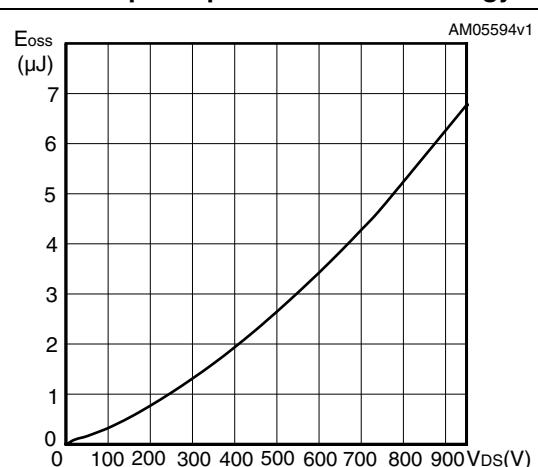
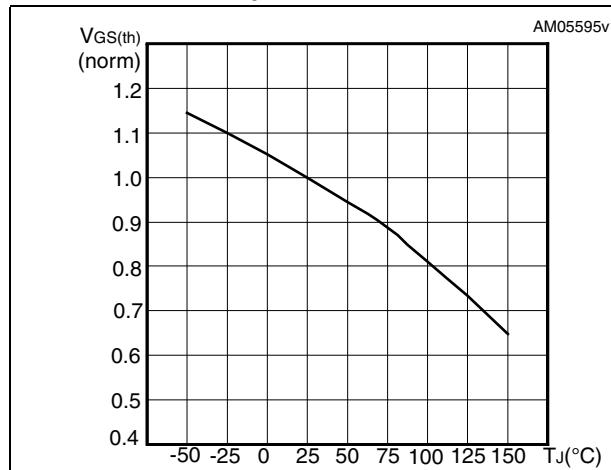
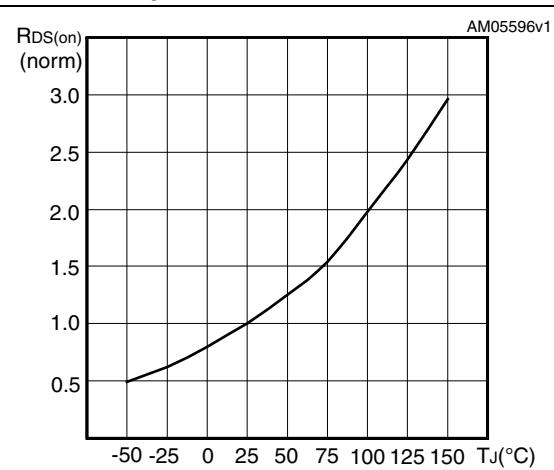
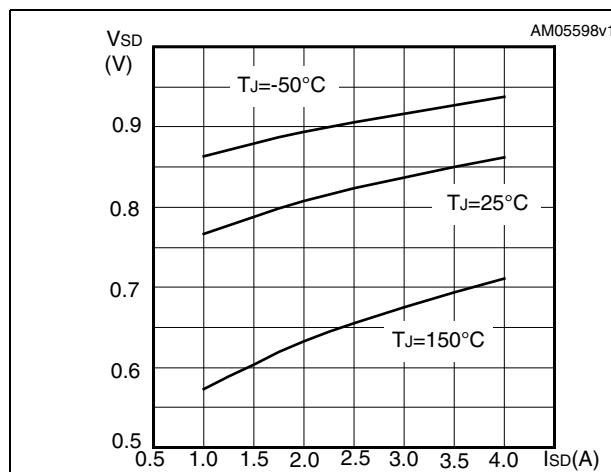
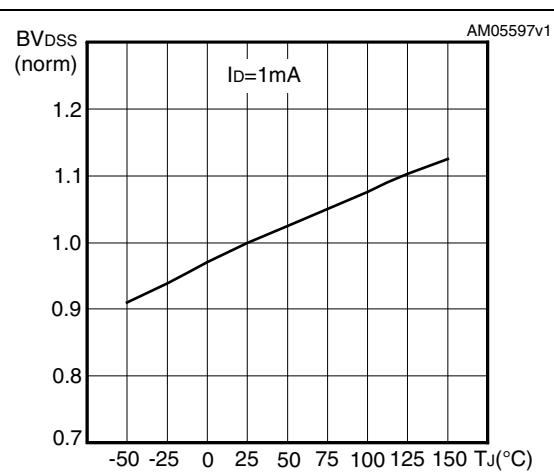
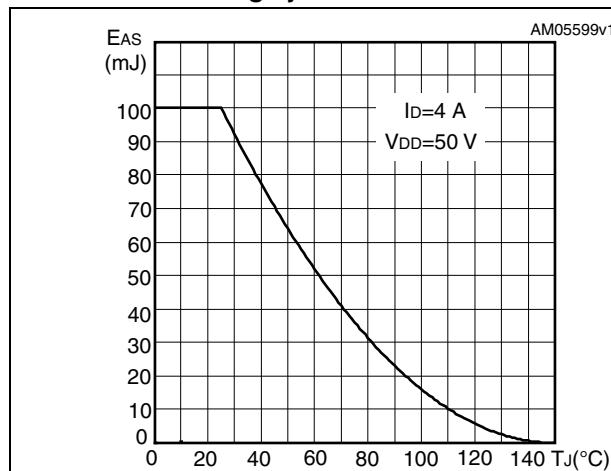


Figure 7. Thermal impedance for IPAK, DPAK

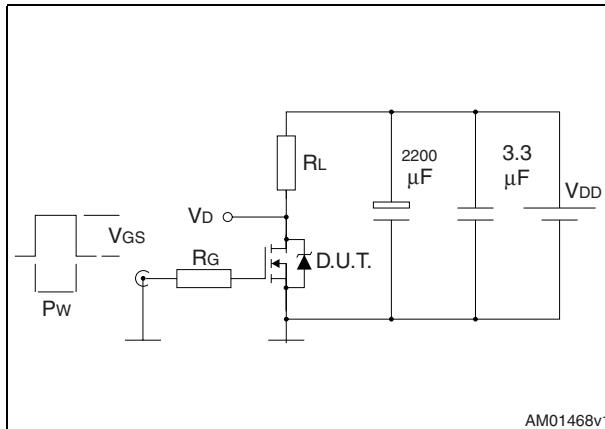


**Figure 8. Output characteristics****Figure 9. Transfer characteristics****Figure 10. Gate charge vs gate-source voltage** **Figure 11. Static drain-source on resistance****Figure 12. Capacitance variations****Figure 13. Output capacitance stored energy**

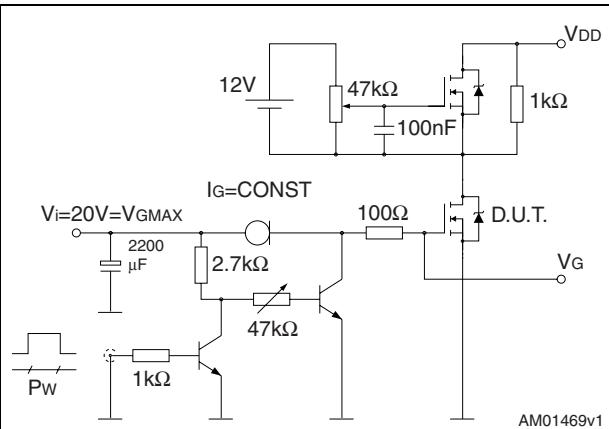
**Figure 14. Normalized gate threshold voltage vs temperature****Figure 15. Normalized on resistance vs temperature****Figure 16. Source-drain diode forward characteristics****Figure 17. Normalized B<sub>VDSS</sub> vs temperature****Figure 18. Maximum avalanche energy vs starting T<sub>j</sub>**

### 3 Test circuits

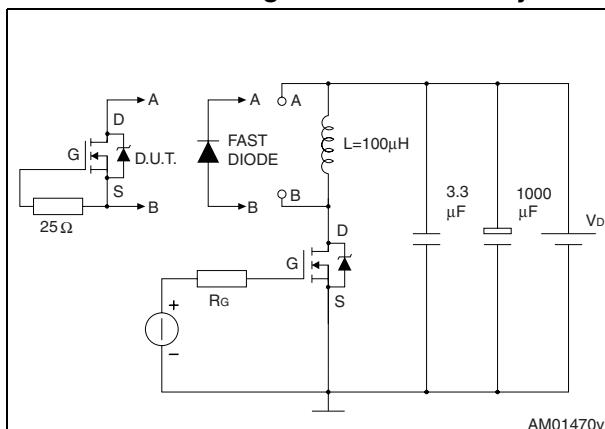
**Figure 19. Switching times test circuit for resistive load**



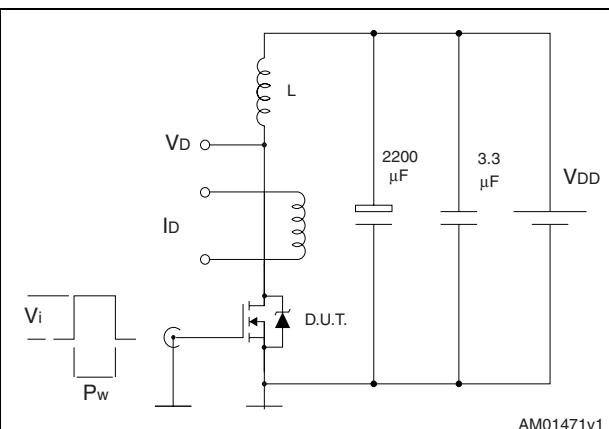
**Figure 20. Gate charge test circuit**



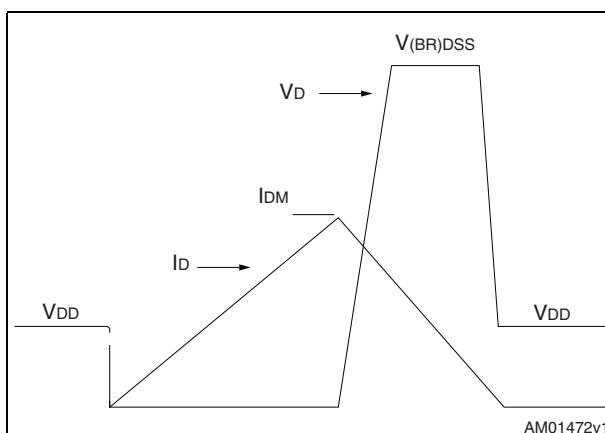
**Figure 21. Test circuit for inductive load switching and diode recovery times**



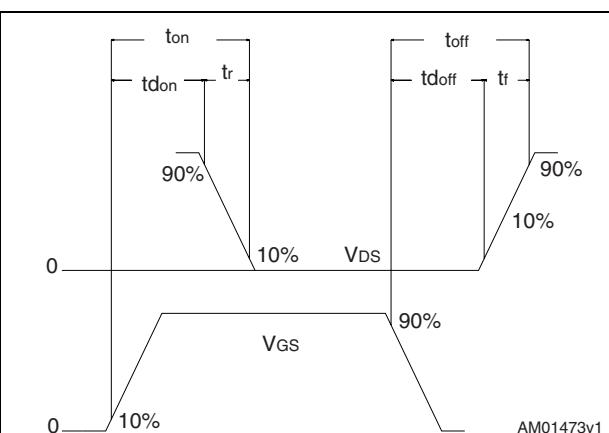
**Figure 22. Unclamped inductive load test circuit**



**Figure 23. Unclamped inductive waveform**



**Figure 24. Switching time waveform**

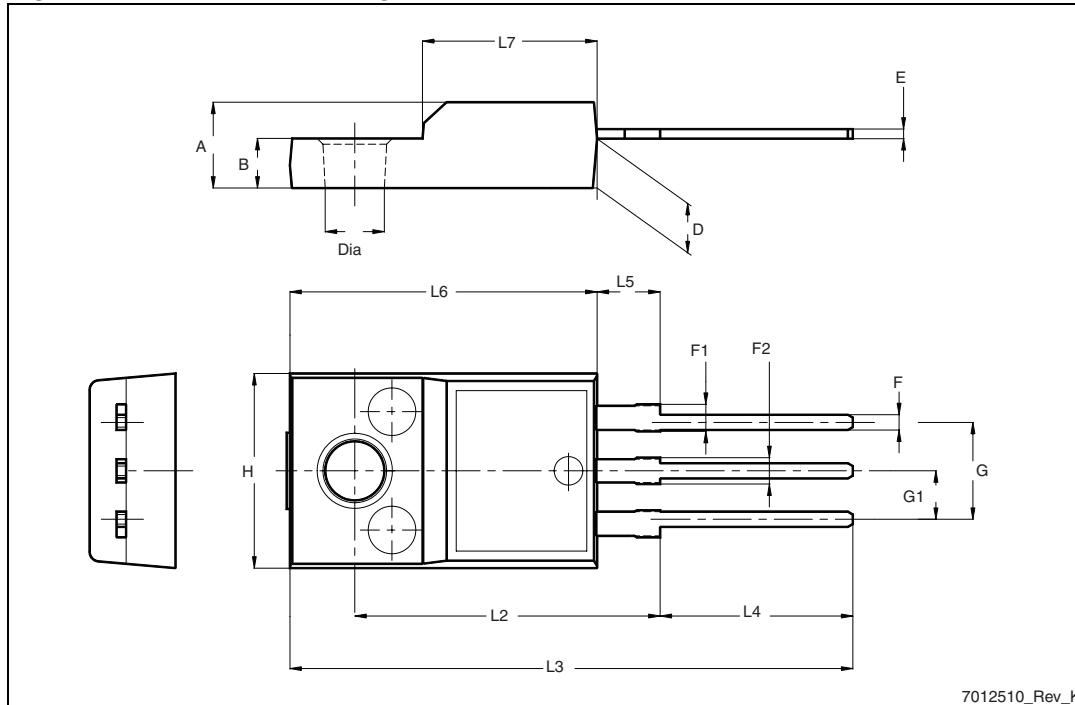


## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

**Table 9.** TO-220FP mechanical data

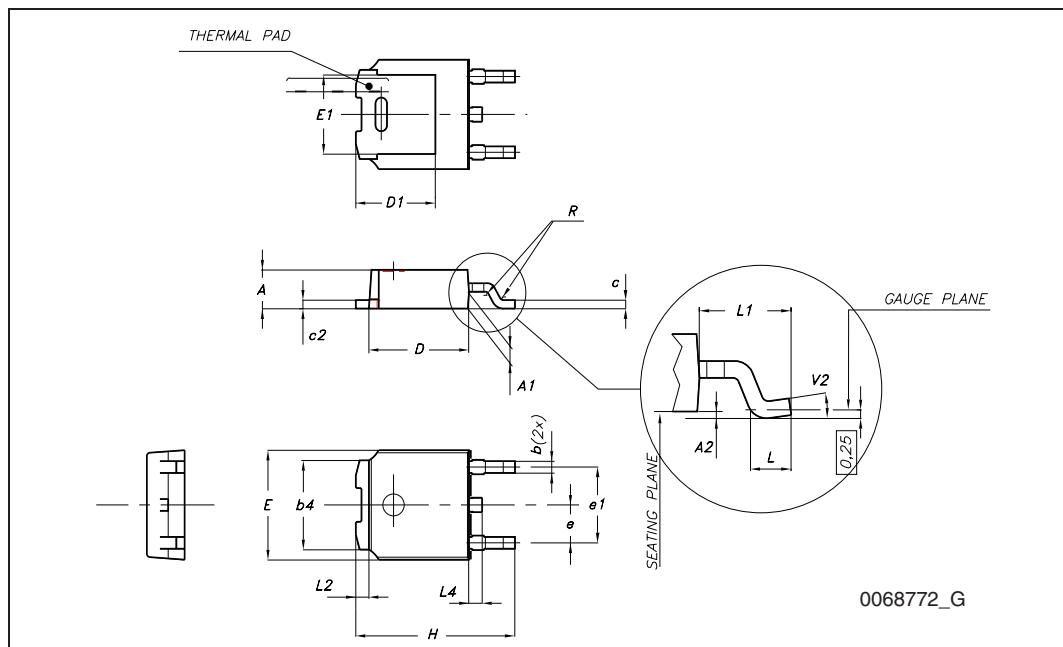
Dim.	mm		
	Min.	Typ.	Max.
A	4.4		4.6
B	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
H	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

**Figure 25.** TO-220FP drawing

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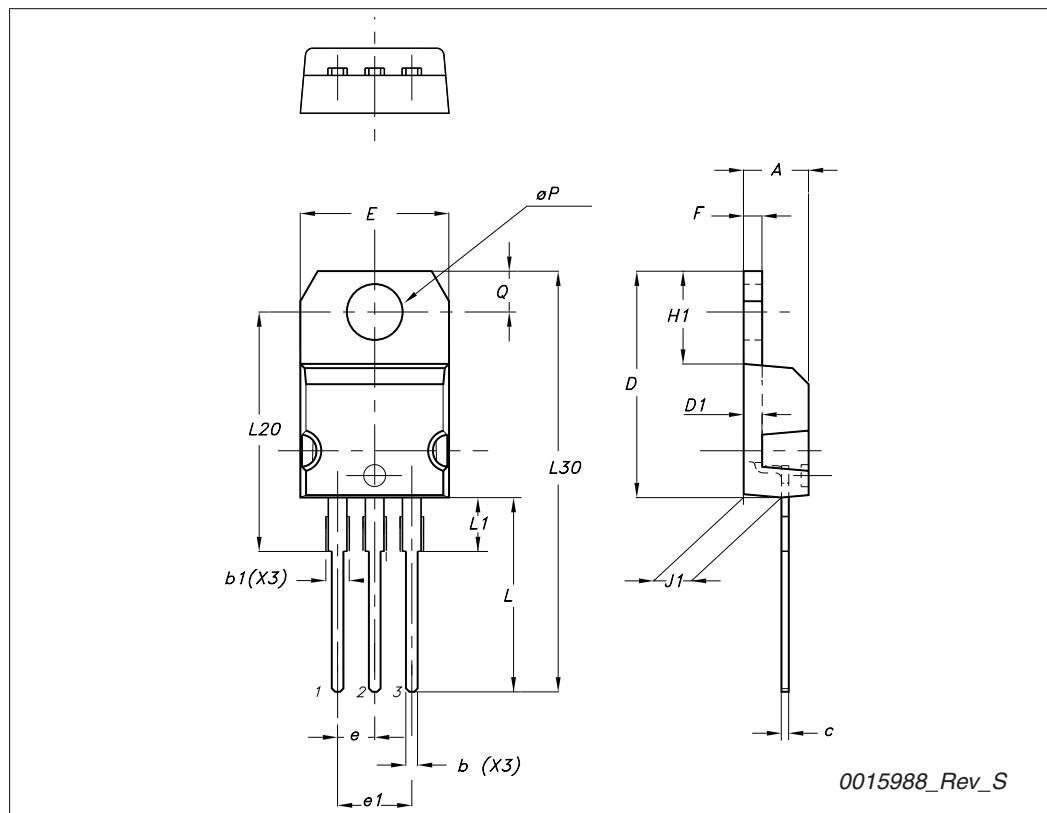
## TO-252 (DPAK) mechanical data

DIM.	mm.		
	min.	typ	max.
A	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1		5.10	
E	6.40		6.60
E1		4.70	
e		2.28	
e1	4.40		4.60
H	9.35		10.10
L	1		
L1		2.80	
L2		0.80	
L4	0.60		1
R		0.20	
V2	0 °		8 °



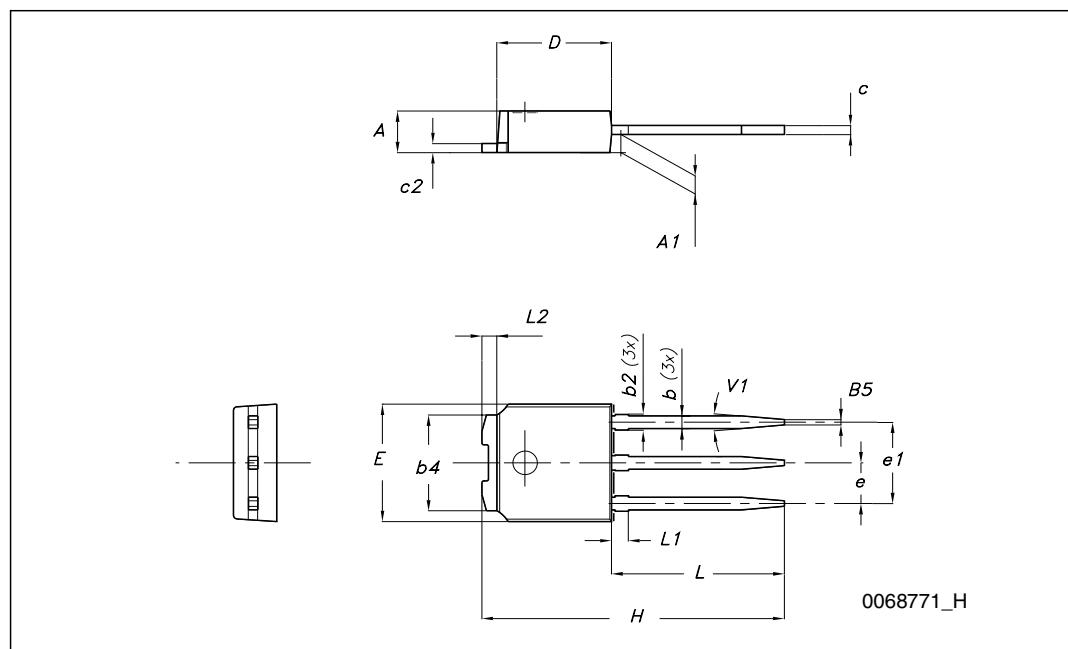
## TO-220 type A mechanical data

Dim	mm		
	Min	Typ	Max
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
$\varnothing P$	3.75		3.85
Q	2.65		2.95



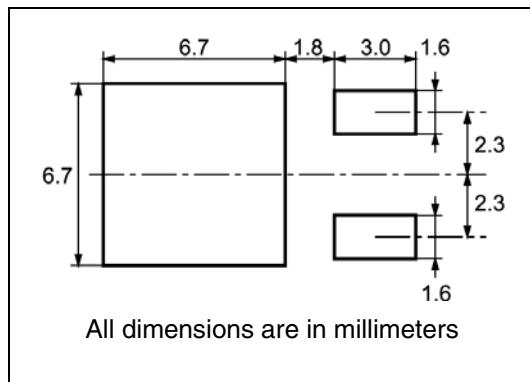
## TO-251 (IPAK) mechanical data

DIM.	mm.		
	min.	typ	max.
A	2.20		2.40
A1	0.90		1.10
b	0.64		0.90
b2			0.95
b4	5.20		5.40
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
E	6.40		6.60
e		2.28	
e1	4.40		4.60
H		16.10	
L	9.00		9.40
(L1)	0.80		1.20
L2		0.80	
V1		10°	



## 5 Packaging mechanical data

### DPAK FOOTPRINT



### TAPE AND REEL SHIPMENT

REEL MECHANICAL DATA				
DIM.	mm		inch	
	MIN.	MAX.	MIN.	MAX.
A		330		12.992
B	1.5		0.059	
C	12.8	13.2	0.504	0.520
D	20.2		0.795	
G	16.4	18.4	0.645	0.724
N	50		1.968	
T		22.4		0.881

BASE QTY	BULK QTY
2500	2500

TAPE MECHANICAL DATA				
DIM.	mm		inch	
	MIN.	MAX.	MIN.	MAX.
A0	6.8	7	0.267	0.275
B0	10.4	10.6	0.409	0.417
B1		12.1		0.476
D	1.5	1.6	0.059	0.063
D1	1.5		0.059	
E	1.65	1.85	0.065	0.073
F	7.4	7.6	0.291	0.299
K0	2.55	2.75	0.100	0.108
P0	3.9	4.1	0.153	0.161
P1	7.9	8.1	0.311	0.319
P2	1.9	2.1	0.075	0.082
R	40		1.574	
W	15.7	16.3	0.618	0.641

## 6 Revision history

**Table 10. Document revision history**

Date	Revision	Changes
12-May-2009	1	First release
11-Dec-2009	2	Document status promoted from preliminary data to datasheet

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